Notice of References Cited

Application/Control No.

10/725,239

Examiner

Michael D Masinick

Applicant(s)/Patent Under
Reexamination
LIN ET AL.

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,308,107 B1	10-2001	Conboy et al.	700/121
	В	US-6,748,287 B1	06-2004	Hagen et al.	700/99
	С	US-6,564,113 B1	05-2003	Barto et al.	700/99
	D	US-6,725,113 B1	04-2004	Barto et al.	700/99
	E	US-6,535,778 B2	03-2003	Okabe et al.	700/112
	.F	US-2003/0171972 A1	09-2003	Heskin, James	705/9
	G	US-6,049,742 A	04-2000	Milne et al.	700/99
	Н	US-4,802,094	01-1989	Nakamura et al.	700/115
	-	US-			:
-	J	US-			:
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					:
	R					:
	S					
	Т	·				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	υ	"Shifting Bottleneck Detection" - Roser et al, Toyota Central Research and Development Labs, 2002 Winter Simulation Conference
*	٧	"Semiconductor Factory Automation: Designing for Phased Automation" - Gardner et al, Hewlett-Packard Corporation, IEEE 1996
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.